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"For contributions to power systems reliability analysis and assessment."

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"For fundamental contributions in the field of fault-tolerant computing"

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"For contributions to the engineering and understanding of interconnect reliability in integrated circuits"

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"For contributions to the reliability of microwave power devices."

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"For development and commercialization of CMOS radio frequency micro electro mechanical systems"

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"For leadership in improving semiconductor reliability test methods"

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"For contributions to high-performance automatic test equipment."

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"For contributions to reliability analysis of high assurance systems"

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"For contributions to the theory and applications of quantitative reliability methods in electric power systems."

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"For contributions to electrostatic discharge devices and design protection methods for integrated circuit applications."

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"For contributions to power system operation and planning in uncertain environments"

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"For contributions to access control and combinatorial test methods."

Deepak Goyal - Intel Corp. - USA

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"For contributions to fault isolation and failure analysis"

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"For contributions to reliability and characterization of silicon-on-insulator devices and materials"

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"For contributions to the study of multiway channels in information theory."

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"For contributions to neutron-induced soft-error analysis for semiconductor memory devices"

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"For contributions to reliability of compound semiconductor devices"

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"For contributions to the reliability physics of compound semiconductor devices"

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"For contributions to analytical techniques for modeling the reliability of software and systems."

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"For contributions to the implementation of radiation hardened silicon-on-sapphire and silicon-on-insulator technologies."

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"For contributions to software assurance and verification"

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"For contributions to semiconductor process technology to improve radiation hardening of MOS devices"

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"For contributions to hardware, software, and human reliability and risk analysis."

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"For contributions to reliability and performance analysis of computer and communication systems"

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"For development of wafer scale packaging, and plastic packaging."

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"For contributions to the devices physics of heavy doping effects and the development of high voltage integrated circuits for telecommunications switching systems."

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"For contributions to distance learning in electrical and computer engineering education"

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"For contributions to integrated circuits security and trust"

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"For contributions to the field of reliability engineering."

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"For contributions to software reliability engineering and software fault tolerance."

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"For contributions modeling and analysis of systems and software reliability."

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"For contributions to engineering of reliable software-based systems."

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"For contributions to empirical software engineering and data-driven software development."

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"For leadership in software engineering education"

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"For contributions to the field of cost effective, reliable microelectronics packaging."

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"For contributions in industrial training in the fields of semiconductor reliability and failure analysis."

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"For contributions to metalization of and metrology for multilevel interconnects and electronic packaging."

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"For contributions to the analysis and modeling of the cost and sustainment of electronic systems."

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"For leadership in engineering education and for contributions to software and systems education."

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"For contributions to reliability prediction for electronic packaging"

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"For leadership in developing computational tools for healthcare enterprises"

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"For contributions to reliable computing."

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"For contributions to development and education in power system reliability evaluation."

Samuel Keene - Six Sigma Senior Master Black Belt, Seagate Technology - USA

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"For leadership in developing educational products, student and chapter outreach training programs and annual student scholarship programs"

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"For contributions to the design of Structured Object-Oriented Formal Language"

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"For leadership in engineering development of LED packaging"

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"For advances in pattern-oriented intrusion detection and fault-tolerant protection"

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"For his development of safety solutions for electronic equipment."

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"For contributions to reliability in ultra-thin-oxide complementary metal oxide semiconductor (CMOS) devices"

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"For contributions to synchronization and security in automation networks"

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"For contributions to, and technical leadership in, the field of reliability engineering."

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"For contributions to reliability, accelerated test analysis, and reliability education."

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"For leadership in reliability management"

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"For contributions to semiconductor memory reliability"

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"For contributions to electronic product reliability."
